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International Symposium on  
Defect and Fault-Tolerance in  
VLSI Systems**

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# Table of Contents: DFT 2006

## 21<sup>st</sup> IEEE International Symposium on Defect and Fault-Tolerance in VLSI Systems

**Message from the Symposium Chairs** \_\_\_\_\_ **xi**

### **Invited Talk**

Single-Event-Upset Trends in Advanced CMOS Technologies

*David Heidel*

### **Session 1: Adaptive Design and Gate Level Redundancy**

Adaptive Design for Performance-Optimized Robustness \_\_\_\_\_ 3

*Ramyanshu Datta, Jacob Abraham, Abdulkadir Utku Diril,  
Abhijit Chatterjee, and Kevin Nowka*

Employing On-Chip Jitter Test Circuit for Phase Locked Loop Self-Calibration \_\_\_\_\_ 12

*Tian Xia, Stephen Wyatt, and Rupert Ho*

Improving Yield and Defect Tolerance in Multifunction Subthreshold CMOS Gates \_\_\_\_\_ 20

*Kristian Granhaug and Snorre Aunet*

Gate Failures Effectively Shape Multiplexing \_\_\_\_\_ 29

*Valeriu Beiu, Walid Ibrahim,  
Yaser Ali Alkhawwar, and Mawahib Sulieman*

### **Session 2: Delay Test**

Test Generation for Open Defects in CMOS Circuits \_\_\_\_\_ 41

*Narendra Devta-Prasanna, Arun Gunda,  
Prabhakaran Krishnamurthy, Sudhakar Reddy, and Irith Pomeranz*

Implicit Critical PDF Test Generation with Maximal Test Efficiency \_\_\_\_\_ 50

*Kyriakos Christou, Maria Michael, and Spyros Tragoudas*

Selecting High-Quality Delay Tests for Manufacturing Test and Debug \_\_\_\_\_ 59

*Hangkyu Lee, Suriyaprakash Natarajan,  
Srinivas Patil, and Irith Pomeranz*

### **Session 3: Emerging Technologies**

Testing Reversible 1D Arrays for Molecular QCA <i>Xiaojun Ma, Jing Huang, Cecilia Metra, and Fabrizio Lombardi</i>	71
Efficient and Robust Delay-Insensitive QCA (Quantum-Dot Cellular Automata) Design <i>Minsu Choi, Myungsu Choi, Zachary Patitz, and Nohpill Park</i>	80
Error Tolerance of DNA Self-Assembly by Monomer Concentration Control <i>Yong-Bin Kim, Byunghyun Jang, and Fabrizio Lombardi</i>	89
Inherited Redundancy and Configurability Utilization for Repairing Nanowire Crossbars with Clustered Defects <i>Minsu Choi, Yadunandana Yellambalase, and Yong-Bin Kim</i>	98
A Reconfiguration-Based Defect Tolerance Method for Nanoscale Devices <i>Mohammad Tehranipoor and Reza Rad</i>	107

### **Session 4: Test Compression**

Reducing ATE Bandwidth and Memory Requirements: A Diagnosis Friendly Scan Test Response Compactor <i>Sverre Wichlund, Frank Berntsen, and Einar J Aas</i>	119
A Novel Methodology for Functional Test Data Compression by ATE <i>Hamidreza Hashempouour and Fabrizio Lombardi</i>	128
Low-Cost IP Core Test Using Multiple-Mode Loading Scan Chain and Scan Chain Clusters <i>Toshinori Takabatake, Gang Zeng, Youhua Shi, and Hideo Ito</i>	136
An Efficient Scan Chain Partitioning Scheme with Reduction of Test Data Under Routing Constraint <i>Geewhun Seok, Il-Soo Lee, Tony Ambler, and Baxter F. Womack</i>	145

### **Invited Talk**

Reconfiguration-Based Defect Tolerance for Microfluidic Biochips <i>Krishnendu Chakrabarty</i>	
---	--

## **Session 5: Defect Tolerance and Error Correction**

Defect Tolerant and Energy Economized DSP Plane of a 3-D Heterogeneous SoC _____	157
<i>Vijay Jain and Glenn Chapman</i>	
Fuse Area Reduction Based on Quantitative Yield Analysis and Effective Chip Cost _____	166
<i>Akhil Garg and Prashant Dubey</i>	
Low-Density Triple-Erasure Correcting Codes for Dependable Distributed Storage Systems _____	175
<i>Haruhiko Kaneko, Eiji Fujiwara, and Hiroyuki Ohde</i>	
Modified Triple Modular Redundancy Structure Based on Asynchronous Circuit Technique _____	184
<i>Gong Rui, Chen Wei, Liu Fang, Dai Kui, and Wang Zhiying</i>	

## **Session 6: BIST and Pseudo-Functional Test**

Low Power SoC Memory BIST _____	197
<i>Yuejian Wu and Andre Ivanov</i>	
Synthesis of Efficient Linear Test Pattern Generators _____	206
<i>Avijit Dutta and Nur Touba</i>	
An Approach to Minimizing Functional Constraints _____	215
<i>Abhijit Jas, Yi-Shing Chang, and Sreejit Chakravarty</i>	

## **Session 7: Reliability Evaluation and Analysis**

Reliability Evaluation of Repairable/Reconfigurable FPGAs _____	227
<i>Marco Ottavi, Salvatore Pontarelli, Vamsi Vankamamidi, Adelio Salsano, and Fabrizio Lombardi</i>	
Reliability Analysis of Self-Repairable MEMS Accelerometer _____	236
<i>Xingguo Xiong, Yu-Liang Wu, and Wen-Ben Jone</i>	
Timing Failure Analysis of Commercial CPUs under Operating Stress _____	245
<i>Gwan Choi and Sanghoan Chang</i>	
Real Time Fault Injection Using Enhanced OCD—A Performance Analysis _____	254
<i>Andre Fidalgo, Gustavo Alves, and Jose Ferreira</i>	

## Session 8: Approaches for Soft Errors

Combined Software and Hardware Techniques for the Design of Reliable IP Processors _____	265
<i>Cristiana Bolchini, Antonio Miele, Maurizio Rebaudengo, Donatella Sciuto, Luca Sterpone, and Massimo Violante</i>	
Low-Cost Hardening of Image Processing Applications against Soft Errors _____	274
<i>Ilija Polian, Bernd Becker, Masato Nakazato, Satoshi Ohtake, and Hideo Fujiwara</i>	
Online Hardening of Programs against SEUs and SETs _____	280
<i>Carlos Lisboa, Luigi Carro, Matteo Reorda, and Massimo Violante</i>	

## Session 9: Interactive Papers

Equivalent $I_{DDQ}$ Tests for Systems with Regulated Power Supply _____	291
<i>Chuen-Song Chen, Jien-Chung Lo, and Tian Xia</i>	
Self Testing SoC with Reduced Memory Requirements and Minimized Hardware Overhead _____	300
<i>Ondřej Novák, Zdeněk Pliva, Jiří Jeníček, Zbyněk Mader, and Michal Jarkovský</i>	
Bilateral Testing of Nano-Scale Fault-Tolerant Circuits _____	309
<i>Lei Fang and Michael Hsiao</i>	
A Metric of Tolerance for the Manufacturing Defects of Threshold Logic Gates _____	318
<i>Sandeep Dechu, Spyros Tragoudas, and Manoj Kumar Goparaju</i>	
Soft Error Masking Circuit and Latch Using Schmitt Trigger Circuit _____	327
<i>Yoichi Sasaki, Kazuteru Namba, and Hideo Ito</i>	
Influence of Resistive Bridging Fault on Crosstalk Coupling Effects in On-Chip Aggressor-Victim Interconnects _____	336
<i>Kishore Kumar Duganapalli, Ajoy Kumar Palit, and Walter Anheier</i>	
SET Fault Tolerant Combinational Circuits Based on Majority Logic _____	345
<i>Carlos Lisboa, Lorenzo Petroli, Alisson Michels, Fernanda Kastensmidt, and Luigi Carro</i>	
An Improved Reconfiguration Method for Degradable Processor Arrays Using Genetic Algorithm _____	353
<i>Yusuke Fukushima, Masaru Fukushi, and Susumu Horiguchi</i>	
A Built-In Redundancy-Analysis Scheme for Self-Repairable RAMS with Two-Level Redundancy _____	362
<i>Jin-Fu Li, Yu-Jen Huang, and Da-Ming Chang</i>	

Design and Evaluation of a Hardware On-Line Program-Flow Checker for Embedded Microcontrollers _____	371
<i>Marco Ottavi, Salvatore Pontarelli, Alessandro Leandri, and Adelio Salsano</i>	
Recovery Mechanisms for Dual Core Architectures _____	380
<i>Christian El Salloum, Andreas Steininger, Peter Tummeltshammer, and Werner Harter</i>	
A Software-Based Error Detection Technique Using Encoded Signatures _____	389
<i>Yasser Sedaghat, Seyed Ghassem Miremadi, and Mahdi Fazeli</i>	

### **Session 10: Diagnosis**

Effective Post-BIST Fault Diagnosis for Multiple Faults _____	401
<i>Hiroshi Takahashi, Shuhei Kadoyama, Yoshinobu Higami, Yuzo Takamatsu, Koji Yamazaki, Takashi Aikyo, and Yasuo Sato</i>	
Fault Diagnosis of Analog Circuits Based on Adaptive Test and Output Characteristics _____	410
<i>Yukiya Miura and Jiro Kato</i>	
Scan-Based Delay Fault Tests for Diagnosis of Transition Faults _____	419
<i>Irith Pomeranz and Sudhakar Reddy</i>	
Enhancing Diagnosis Resolution for Delay Faults by Path Extension Method _____	428
<i>Ying-Yen Chen and Jing-Jia Liou</i>	

### **Session 11: Defect and Fault Tolerance in Sensors and NOCs**

On-Line Mapping of In-Field Defects in Image Sensor Arrays _____	439
<i>Jozsef Dudas, Cory Jung, Linda Wu, Glenn Chapman, Israel Koren, and Zahava Koren</i>	
Fault Tolerant Active Pixel Sensors in 0.18 and 0.35 Micron Technologies _____	448
<i>Glenn Chapman, Michelle La Haye, Cory Jung, David Chen, and Jozsef Dudas</i>	
NoC Interconnect Yield Improvement Using Crosspoint Redundancy _____	457
<i>Cristian Grecu, Partha Pratim Pande, André Ivanov, and Res Saleh</i>	
Design of Low Power and Reliable Networks on Chip through Joint Crosstalk Avoidance and Forward Error Correction Coding _____	466
<i>Partha Pratim Pande, Amlan Ganguly, Brett Feero, Benjamin Belzer, and Cristian Grecu</i>	

## Session 12: Test Techniques

Thermal-Aware SoC Test Scheduling with Test Set Partitioning and Interleaving _____	477
<i>Zhiyuan He, Zebo Peng, Petru Eles, Paul Rosinger, and Bashir Al-Hashimi</i>	
Load Board Designs Using Compound Dot Technique and Phase Detector for Hierarchical ATE Calibrations _____	486
<i>Yong-Bin Kim, Fengming Zhang, Warren Necochea, Peter Reiter, and Fabrizio Lombardi</i>	
Multi-Site and Multi-Probe Substrate Testing on an ATE _____	495
<i>Xiaojun Ma and Fabrizio Lombardi</i>	

## Session 13: Processor Checking and Jitter

Off-Chip Control Flow Checking of On-Chip Processor-Cache Instruction Stream _____	507
<i>Shantanu Dutt, Federico Rota, and Sahithi Krishna</i>	
The Filter Checker: An Active Verification Management Approach _____	516
<i>Joonhyuk Yoo and Manoj Franklin</i>	
Effect of Process Variation on the Performance of Phase Frequency Detector _____	525
<i>Nandakumar Venugopal, Nihal Shastry, and Shambhu Upadhyaya</i>	
Data Dependent Jitter Characterization Based on Fourier Analysis _____	534
<i>Di Mu, Tian Xia, and Hao Zheng</i>	

## Session 14: Fault Tolerant Designs

A 3-Port Register File Design for Improved Fault Tolerance on Resistive Defects in Core-Cells _____	545
<i>Lushan Liu, Ramalingam Sridhar, and Shambhu Upadhyaya</i>	
A Multiple-Weight-and-Neuron-Fault Tolerant Digital Multilayer Neural Network _____	554
<i>Tadayoshi Horita, Takurou Murata, and Itsuo Takanami</i>	
VLSI Implementation of a Fault-Tolerant Distributed Clock Generation _____	563
<i>Gottfried Fuchs, Markus Ferringer, Andreas Steininger, and Gerald Kempf</i>	
Parity-Based Fault Detection Architecture of S-box for Advanced Encryption Standard _____	572
<i>Arash Reyhani-Masoleh and Mehran Mozaffari Kermani</i>	

<b>Author Index</b> _____	<b>581</b>
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